SN54F374, SN74F374 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS

SDFS077A - D2932, MARCH 1987 - REVISED OCTOBER 1993

- Eight D-Type Flip-Flops in a Single Package
- 3-State Bus-Driving True Outputs
- Full Parallel Access for Loading
- Buffered Control Inputs
- Package Options Include Plastic Small-Outline (SOIC) and Shrink Small-Outline (SSOP) Packages, Ceramic Chip Carriers, and Plastic and Ceramic DIPs

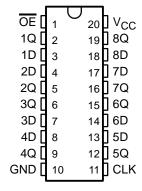
description

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

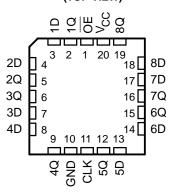
The eight flip-flops of the 'F374 are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels that were set up at the data (D) inputs.

A buffered output enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54F374 . . . J PACKAGE SN74F374 . . . DB, DW, OR N PACKAGE (TOP VIEW)



SN54F374 . . . FK PACKAGE (TOP VIEW)



The output enable (\overline{OE}) input does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN74F374 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN54F374 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74F374 is characterized for operation from 0° C to 70° C.

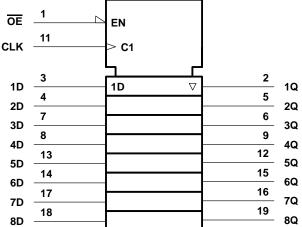
FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT				
OE	CLK	D	Q			
L	↑	Н	Н			
L	\uparrow	L	L			
L	H or L	Χ	Q_0			
Н	Х	Χ	Z			

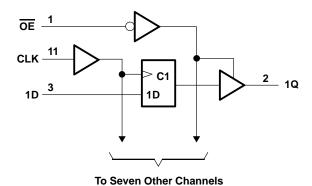


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logic symbol†



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1) .		–1.2 V to 7 V
Input current range		–30 mA to 5 mA
Voltage range applied to any output in	the disabled or power-off state	0.5 V to 5.5 V
Voltage range applied to any output in	the high state	0.5 V to V _{CC}
Current into any output in the low state	: SN54F374	
	SN74F374	48 mA
Operating free-air temperature range:	SN54F374	–55°C to 125°C
	SN74F374	0°C to 70°C
Storage temperature range		65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54F374			SN74F374			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
liK	Input clamp current			-18			-18	mA
ІОН	High-level output current			-3			-3	mA
loL	Low-level output current			20			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54F374			S			
	les	SI CONDITIONS	MIN	TYP†	MAX	MIN	TYP [†]	MAX	UNIT
VIK	V _{CC} = 4.5 V,	I _I = –18 mA			-1.2			-1.2	V
	V _{CC} = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.5	3.4		2.5	3.4		
v_{OH}	VCC = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.4	3.3		2.4	3.3		V
	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA to } -3 \text{ mA}$				2.7			
Voi	V _{CC} = 4.5 V	I _{OL} = 20 mA		0.3	0.5				V
VOL		I _{OL} = 24 mA					0.35	0.5	V
lozh	$V_{CC} = 5.5 \text{ V},$	V _O = 2.7 V			50			50	μΑ
lozl	$V_{CC} = 5.5 \text{ V},$	V _O = 0.5 V			-50			-50	μΑ
lį	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
lіН	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
I _{IL}	V _{CC} = 5.5 V,	V _I = 0.5 V			- 0.6			- 0.6	mA
los [‡]	V _{CC} = 5.5 V,	VO = 0	-60		-150	-60		-150	mA
^I ccz	V _{CC} = 5.5 V,	See Note 2		55	86		55	86	mA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			T _A =	= 5 V, 25°C 374	SN54F374		SN74F374		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	ock Clock frequency		0	100	0	60	0	70	MHz
	Pulse duration	CLK high	7		7		7		ns
t _W		CLK low	6		6		6		
	Outro time data bafana OLKA	High	2		2.5		2		20
t _{su}	Setup time, data before CLK↑	Low	2		2		2		ns
4.	Hold time data after CLKT	High	2		2		2		20
th	Hold time, data after CLK↑	Low	2		2.5		2		ns

[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. NOTE 2: ICCZ is measured with \overline{OE} at 4.5 V and all other inputs grounded.

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switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)			CC = 5 V _ = 50 pl _ = 500 9 \ = 25°C	F, Ω,	C _L R _L	= 50 pF = 500 Ω		V,	UNIT
				′F374		SN54F374		SN74F374		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f _{max}			100			60		70		MHz
^t PLH	CLK	0	3.2	6.1	8.5	3.2	10.5	3.2	10	ns
^t PHL	OLK	Q	3.2	6.1	8.5	3.2	11	3.2	10	115
^t PZH	<u>OE</u>	0	1.2	8.6	11.5	1.2	14	1.2	12.5	20
^t PZL	OE	Q	1.2	5.4	7.5	1.2	10	1.2	8.5	ns
t _{PHZ}	ŌĒ	Q	1.2	4.9	7	1.2	8	1.2	8	ns
^t PLZ		ά	1.2	3.9	5.5	1.2	7.5	1.2	6.5	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



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